

**IN THE UNITED STATES  
PATENT AND TRADEMARK OFFICE**

## **Patent Application**

**Inventors(s):** Stanley Pau  
Donald Milan Tennant                   **Case:** 13-16

**Serial No.:** **Group Art Unit:** Not assigned yet

**Filing Date:** **Examiner:** Not assigned yet

**Title:** Focusable and Steerable Micro-miniature X-ray Apparatus

**THE COMMISSIONER OF PATENTS AND TRADEMARKS  
WASHINGTON, DC 20231**

**SIR:**

## **INFORMATION DISCLOSURE STATEMENT**

In accordance with 37 CFR 1.97(b), the enclosed Information Disclosure Statement (IDS) is submitted for consideration in the above-identified application.

Copies of the reference(s) listed in the IDS are enclosed.

**NO FEE IS REQUIRED.**

Respectfully,

Respectfully,  
  
By \_\_\_\_\_

Michael J. Urbano  
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Reg. No. 24522  
610-691-7710

Date: 11/18/03

**Att. IDS with reference(s)**

APPLICANT: Stanley Pau et al.

## INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

FILING DATE

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
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AA	4	3	4	0	2	8	3	7/82	Cohen	351	161	
AB	5	6	2	8	6	5	9	5/97	Xie et al.	445	3	
AC	6	1	4	8	0	6	1	11/00	Shefer et al.	378	121	
AD	6	2	5	9	7	6	4	7/01	Evans-Lutterodt et al.	378	84	
AE	6	4	4	8	1	0	0	9/02	Schulte et al.	438	20	
AF	6	4	7	7	2	3	3	11/02	Ribbing et al.	378	136	
AG	6	5	9	2	5	2	6	7/03	Lenker	600	463	
AH												
AI												
AJ												
AK												

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY/AUTHOR	CLASS	SUB-CLASS	TRANSL'N YES NO
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AL							
AM							
AN							
AO							
AP							

## OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	Henke et al., Two-channel, elliptical..., Rev. Sci. Instrum., Vol. 56, No. 8, p. 1537 (Aug. 1985)
	AS	Lee et al., High aspect ratio..., J. Vac. Sci. Tech., Vol. B12, No. 6, p. 3425 (Nov/Dec. 1994)
	AT	Tang et al., Emission measurements..., J. Vac. Sci. Tech., Vol. B14, No. 6, p. 3455 (Nov/Dec. 1996)
	AU	Nagao et al., Metal-oxide-semiconductor..., J. Vac. Sci. Tech., Vol. B21, No. 1, p. 495 (Jan/Feb. 2003)
	AV	Busta et al., Characterization of electron..., J. Vac. Sci. Tech., Vol. B21, No. 1, p. 344 (Jan/Feb. 2003)
	AW	Evans-Lutterodt et al., Single-element..., Optics Express, Vol. 11, No. 8, p. 919 (Apr. 2003)
	AX	

EXAMINER:

DATE CONSIDERED:

SHEET 1 OF 1